Supplementary materials

The Growth Mechanism and Intriguing Optical and Electronic Properties of Few Layered HfS₂

Jitendra Singh^{a,b*}, Jia-Hui Shao^a, Guan-Ting Chen^a, Han-Song Wu^a, and Meng-Lin Tsai^{a*}

^aDepartment of Materials Science and Engineering, National Taiwan University of Science and Technology, Taipei 106335, Taiwan

^bDepartment of Physics, Udit Narayan Post Graduate College Padrauna, Kushinagar, Uttar

Pradesh 274304, India

Email: mltsai@mail.ntust.edu.tw



Figure S1: The optical images of as grown few layered HfS_2 (a) onto c-plane sapphire (b) SiO_2/Si substrates, respectively.



Figure S2: (a) Photoluminescence (PL) spectra of as grown HfS_2 onto SiO_2/Si . (b) The XPS spectra of as grown few layered HfS_2 on SiO_2/Si substrate (c) Zoom spectra to check entire suppression of Cl elements. (d) The calculated density of states of the HfS_2 .



Figure S3: (a) Current-voltage (*I-V*) characteristics of fabricated HFS_2 photodetector on cplane sapphire under dark and under UV laser light illuminations at different laser power intensities. (b) The responsivity vs bias voltage curve of the photodetector at different laser intensities. (c) The responsivity curve as a function of power densities at applying bias voltage of 20 V. (d) The *I-V* characteristics of the photodetector under dark and under white light illuminations at different laser power intensities. (e) The responsivity vs bias voltage curve of at different laser intensities. (c) The responsivity curve as a function of power densities at applying bias voltage of 20 V.



Figure S4: The comparison of obtained responsivity under UV, green, and white light illuminations as function of power density at an applied bias voltage of 20 V.